International ICR Rectifier

PD- 93844B

Dual FETKY[™]

and Schottky Diode Ideal for Synchronous Buck DC-DC Converters Up to 5A Peak Output

Co-Pack Dual N-channel HEXFET[®] Power MOSFET

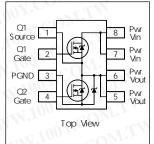
IRF7901D1

Co-Packaged Dual MOSFET Plus Schottky Diode

Device Ratings (Max.Values)

- Low Conduction Losses Low Switching Losses
- Low Vf Schottky Rectifier





	Q1	Q2
	COM	and Schottky
V _{DS}	30V	30V
R _{DS(on)}	38 mΩ	32 mΩ
Q _G	10.5 nC	18.3 nC
Q _{sw}	3.8 nC	9.0 nC
V _{SD}	1.0V	0.52V

Description

The FETKY[™] family of Co-Pack HEXFET[®]MOSFETs and Schottky diodes offers the designer an innovative, board space saving solution for switching regulator and power management applications. Advanced HEXFET®MOSFETs combined with low forward drop Schottky results in an extremely efficient device suitable for a wide variety of portable electronics applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics and multiple die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically reduced board space. Internal connections enable easier board layout design with reduced stray inductance.

Parameter Symbol IRF7901D1 Units V **Drain-Source Voltage** V_{DS} 30 Gate-Source Voltage V_{GS} ±20 **Continuous Output** $T_{1} = 100^{\circ}C$ 6.2 I_{D} A Current ($V_{GS} \ge 4.5V$) ④ Pulsed Drain Current^① I_{DM} 24 Power Dissipation 3 W $T_{1} = 100^{\circ}C$ P_{D} 2.0 °C T_J, T_{STG} -55 to 150 Junction & Storage Temperature Range Pulsed Source Current ① 12 A I_{SM}

Absolute Maximum Ratings

Thermal Resistance

Parameter	WT	Max.	Units
Maximum Junction-to-Ambient3	R _{eja}	62.5	°C/W
Maximum Junction-to-Lead®	R _{ejl}	25	°C/W
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Electrical Characteris	stics	Q1	- Contr	ol FET	Q2	- Synch & Schot	n FET tky	001.0	
Parameter	100	Min	Тур	Max	Min	Тур	Max	Units	Conditions
Drain-to-Source Breakdown Voltage*	BV _{DSS}	30	0 <u>5</u> .	NT.	30	W	<u> 1</u>	Vo	$V_{GS} = 0V, I_{D} = 250 \mu A$
Static Drain-Source on Resistance*	R _{DS} (on)	001	28	38	_ «1	23	32	mΩ	$V_{gs} = 4.5V, I_{D} = 5A^{2}$
Gate Threshold Voltage*	V _{GS} (th)	1.0		N-T	1.0	-	N 2	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Drain-Source Leakage	I _{DSS}	100	80	30	<u>N-</u>	-	30	μA	$V_{\rm DS} = 24 V, V_{\rm GS} = 0$
COM	WW	N - <u>2</u> - N	NT.C	0.15	M	-	4.3	mA	$V_{\rm DS} = 24 V, V_{\rm GS} = 0, T_{\rm J} = 125^{\circ} C$
Gate-Source Leakage Current*	I _{GSS}	47.1	NON.	±100	VTI	-	±100	nA	$V_{GS} = \pm 20V$
Total Gate Charge*	Q _{G cont}	<u>17</u>	7.6	10.5	17	15.5	21.0	NN.	$V_{GS} = 5V, V_{DS} = 16V, I_{D} = 5A$
COM	$Q_{G \text{ synch}}$	N I N	6.7	9.0	Mr.	13.5	18.3	WW	$V_{gs} = 5V, V_{Ds} = 100mV, I_{D} = 5A$
Pre-Vth Gate-Source Charge	Q _{GS1}	WW	2.0	N.C	014.	5.5	-	W	$V_{\rm DS} = 16V, I_{\rm D} = 5A$
Post-Vth Gate-Source Charge	Q _{GS2}	$\overline{M}M$	0.5	.X00	O.	0.9	-	nC	
Gate to Drain Charge	Q _{GD}		1.9	. The	ĊĀ,	4.7	- N		WWWW.100Y.COM
Switch Charge* $(Q_{gs2} + Q_{gd})$	Q _{sw}	-4	2.4	3.8	¥.60	5.6	9.0		
Output Charge*	Q _{oss}		13.5	18.0	1-0	9.0	12.3		$V_{\rm DS} = 16 V, V_{\rm GS} = 0$
Gate Resistance	R _g	-	3.4	M^{-1}	. 7.	4.3	1	Ω	WWW. ODY.COT
Input Capacitance	C _{iss}	-	780	A.	<u></u>	1810	1.5	1	
Output Capacitance	C _{oss}	-	430		100,	310	N-	pF	$V_{DS} = 16V, V_{GS} = 0, f = 1MHz$
Transfer Capacitance	C	-	30		0711	110	100		WW 100Y.C
Turn-On Delay Time	t _d (on)	1 -	7.2		102	10.4	<u>Ort</u> e	W	$V_{DD} = 16V, I_{D} = 5A, V_{GS} = 5V$
RiseTime	t,		13.8		N-10	16.4	ON)	ns	Clamped inductive load See test diagram Fig 17.
Turn-Off Delay Time	t _d (off)	17	14.7	NT.	1.77	14.6	100	1.1	
FallTime	t,		8		<u> - </u>	5.2	<u></u>	T.	

WWW.10	0 <u>7.CON</u>	M.TV	Q1		paral	Q2 & lel Sch	nottky	OM	IN WW.
Parameter	QUY.	Min	Тур	Max	Min	Тур	Max	Units	Conditions
Diode Forward Voltage*②	V _{SD}	M	0.7	1.0	1 4 1	0.48	0.52	V	$I_{s} = 1A, V_{GS} = 0V$
Reverse Recovery Charge	Q _r	CON	62.3	-	<u>7</u>	8.9	160	nC	dI/dt = 700A/us $V_{DS} = 16V, V_{GS} = 0V, I_{S} = 5A$

1 Repetitive rating; pulse width limited by max. junction temperature.

Combined Q1, Q2 I_{\rm RMS} @ Pwr V_{out} pins. Calculated continuous current based on maximum allowable junction temperature; 4 switching or other losses will decrease RMS current capability When mounted on IRNBPS2 design kit. Measured as device T 5 to Pwr leads ($V_{in} \& V_{out}$) Devices are 100% tested to these parameters.

Pulse width \leq 300 µs; duty cycle \leq 2%. 2

³ When mounted on 1 inch square copper board, t < 10 sec.

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Power MOSFET Optimization for DC-DC Converters

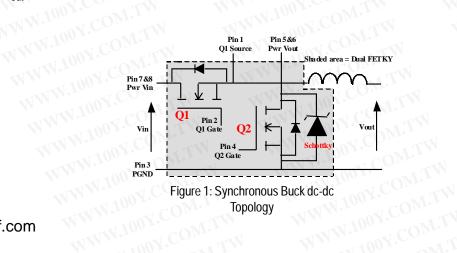
Table 1 and Table 2 describes the event during the various charge segments and shows an approximation of losses during that period.

TW	Description	Segment Losses
Conduction Loss	Losses associated with MOSFET on time. I _{RMS} is a function of load current and duty cycle.	$P_{COND} = I_{RMS}^{2} \times R_{DS(on)}$
Gate Drive Loss	Losses associated with charging and discharging the gate of the MOSFET every cycle. Use the control FET Q_{g} .	$P_{IN} = V_{G} \times Q_{G} \times f$
Switching Loss	Losses during the drain voltage and drain current transitions for every full cycle. Losses occur during the Q_{GS2} and Q_{GD} time period and can be simplified by using Q_{switch} .	$ \begin{array}{ c c c } P_{\text{QGS 2}} \approx V_{\text{IN}} \times I_{\text{L}} \times \frac{Q_{\text{GS 2}}}{I_{\text{G}}} \times \\ P_{\text{QGD}} \approx V_{\text{IN}} \times I_{\text{L}} \times \frac{Q_{\text{GD}}}{I_{\text{G}}} \times J \\ P_{\text{SWITCH}} \approx V_{\text{IN}} \times I_{\text{L}} \frac{Q_{\text{SW}}}{I_{\text{G}}} \times \end{array} $
Output Loss	Losses associated with the Q_{OSS} of the device every cycle when the control FET turns on. Losses are caused by both FETs, but are dissipated by the control FET.	$P_{OUTPUT} = \frac{Q_{OSS}}{2} \times V_{IN} \times f$

	Description	Segment Losses
Conduction Loss	Losses associated with MOSFET on time. I _{RMS} is a function of load current and duty cycle.	$P_{COND} = I_{RMS}^{2} \times R_{DSon}$
Gate Drive Loss	Losses associated with charging and discharging the gate of the MOSFET every cycle. Use the Sync FET Q_{c} .	$P_{IN} = V_{G} \times Q_{G} \times f$
Switching Loss	Generally small enough to ignore except at light loads when the current reverses in the output inductor. Under these conditions various light load power saving techniques are employed by the control IC to maintain switching losses to a negligible level.	$P_{\text{SWITCH}} \approx 0$ $P_{\text{OUTPUT}} = \frac{Q_{\text{OSS}}}{2} \times V_{\text{IN}} \times f$
Output Loss	Losses associated with the Q _{oss} of the device every cycle when the control FET turns on. They are caused by the synchronous FET, but are dissipated in the control FET.	

Typical Application

The performance of the new Dual FETKYTM has been tested in-circuit using IR's new IRNBPS2 "Dual Output Synchronous Buck Design Kit", operating up to 21Vin and 5A peak output current, with operating voltages from 1V_{out} to 5V_{out}.



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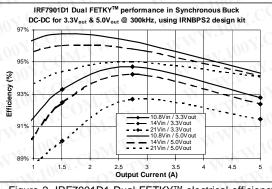
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Typical Application (Contd.)

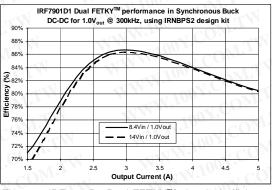
The Dual FETKY integrates all the power semiconductor devices for DC-DC conversion within one SO-8 package, as shown on page 1. The high side control MOSFET (Q1) is optimized for low combined Q_{sw} and $R_{DS}(on)$. The low side synchronous MOSFET (Q2) is optimized for low $R_{DS}(on)$ and high Cdv/dt immunity. The ultra-low V_f schottky diode is internally connected in parallel with the synchronous MOSFET, for improved deadtime efficiency. For ease of circuit board layout, the Dual FETKY has been internally configured such that it represents a functional block for the power device portion of the synchronous buck DC-DC converter. This helps to minimize the external PCB traces compared to a discrete solution.

In-Circuit Efficiency

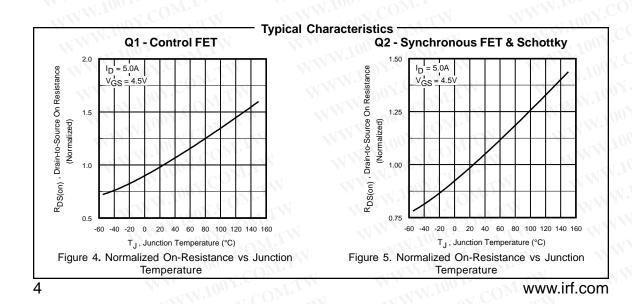
The in-circuit efficiency curves for the Dual FETKY are shown in Figure 2 & 3. The Dual FETKY can achieve up to 96.6% and 94.6% peak efficiency for the 5.0V and 3.3V applications respectively, with excellent maximum load efficiency.





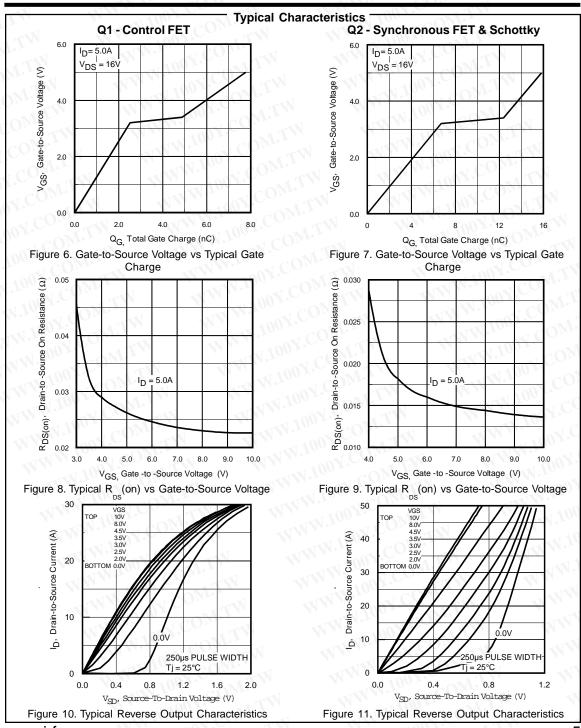




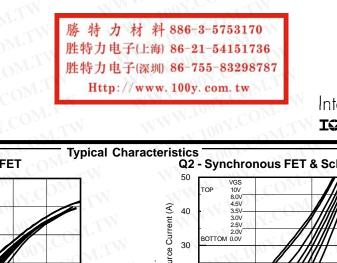


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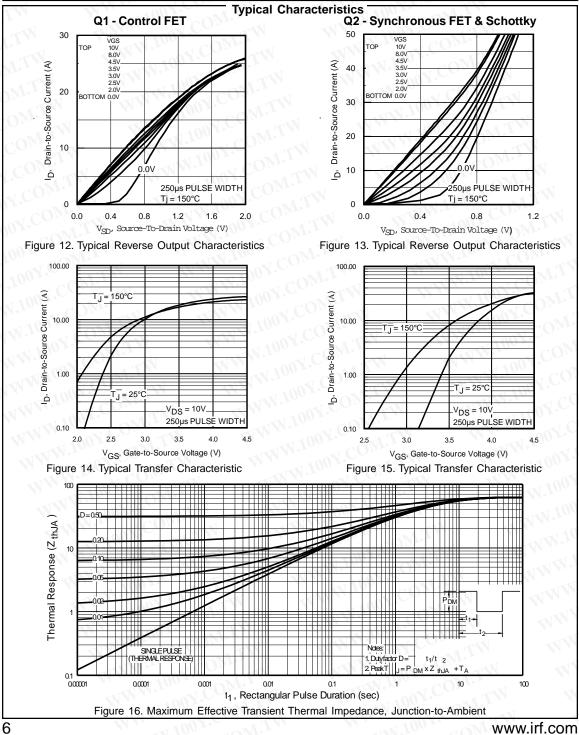


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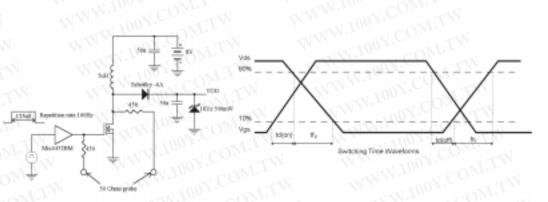


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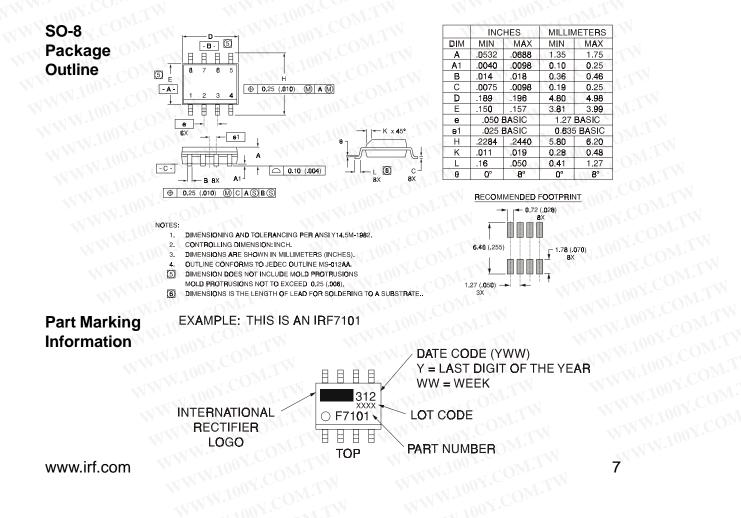


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Figure 17. Clamped Inductive Load Test Diagram and Switching waveform.

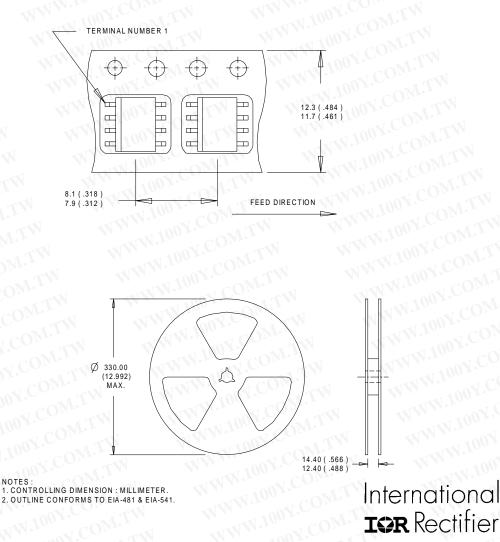


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SO-8 Tape & Reel Information

Dimensions are shown in millimeters (inches)



Data and specifications subject to change without notice. This product has been designed and qualified for the consumer market. Qualification Standards can be found on IR's Web site.

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